

RELIABILITY TEST REPORT

TESTITEM : 1.ELECTRICAL
2.MECHANICAL
3.ENVIRONMENTAL

SERIES NO. : CI42 Series For ACES Housing & Terminal

Terminal:88232 T

Housing:88232-**00

CviLux Wafer:CI42**M2HR*-NH (Halogen-Free)

ACES Wafer:88231-*****-**

TEST EQUIPMENT : 1.INSERTION & REMOVAL APPARATUS
2.ELECTRONIC MEASURING APPARATUS
3.ENVIRONMENTAL APPARATUS

DATE OF TESTING :2009'-03/17

TEST DEPART : R&D

TESTER : Eager

CONTAIN : ATTACHED



REVIEWED : Alex APPROVED : David VERIFIED : Eager .

1.ELECTRICAL PERFORMANCE :

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|-----|---------------------|---------------------------------------------------------|-----------------|-------------|---------------------------------------|
| | | | | Sample | |
| 1-1 | Contact resistance | Dry circuit of DC 20 mV max.,100 mA max. | Less than 20 mΩ | | 20 mΩ max. |
| | | | | | CviLux Wafer VS ACES Housing&Terminal |
| | | | | 1 | 8.9 mΩ |
| | | | | 2 | 9.1 mΩ |
| | | | | 3 | 9.8 mΩ |
| | | | | 4 | 9.6 mΩ |
| | | | | 5 | 9.5 mΩ |
| | | | | Min. | 8.9 mΩ |
| | | | | Max. | 9.8 mΩ |
| | | | | Ave. | 9.38 mΩ |
| | | | | | ACES Wafer VS ACES Housing&Terminal |
| | | | | 1 | 14.1 mΩ |
| | | | | 2 | 14.5 mΩ |
| | | | | 3 | 15.2 mΩ |
| | | | | 4 | 14.8 mΩ |
| | | | | 5 | 14.2 mΩ |
| | | | | Min. | 14.1 mΩ |
| | | | | Max. | 15.2 mΩ |
| | | | | Ave. | 14.56 mΩ |
| 1-2 | Dielectric strength | When applied AC 500V 1 minute between adjacent terminal | No change | | 500 V 1 minute |
| | | | | | CviLux Wafer VS ACES Housing&Terminal |
| | | | | 1 | Pass |
| | | | | 2 | Pass |
| | | | | 3 | Pass |
| | | | | 4 | Pass |
| | | | | 5 | Pass |
| | | | | | ACES Wafer VS ACES Housing&Terminal |
| | | | | 1 | Pass |
| | | | | 2 | Pass |
| | | | | 3 | Pass |
| | | | | 4 | Pass |
| | | | | 5 | Pass |

| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|------|------------------------------------------------------------------------------------------|------------------|------------------------------------------|-----------------------|
| | | | Sample | |
| 1-3 | Insulation resistance When applied DC 500 V between adjacent terminal or ground | More than 100 MΩ | Sample | 100 MΩ min. |
| | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | 1.4x10 ⁶ |
| | | | 2 | 1.4 x10 ⁶ |
| | | | 3 | 1.6 x10 ⁶ |
| | | | 4 | 1.6 x10 ⁶ |
| | | | 5 | 1.8 x10 ⁶ |
| | | | Min. | 1.4 x10 ⁶ |
| | | | Max. | 1.8 x10 ⁶ |
| | | | Ave. | 1.56 x10 ⁶ |
| | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | 1 | 4 x10 ⁶ |
| | | | 2 | 1.4 x10 ⁶ |
| | | | 3 | 1 x10 ⁶ |
| | | | 4 | 5 x10 ⁶ |
| | | | 5 | 3 x10 ⁶ |
| | | | Min. | 1 x10 ⁶ |
| | | | Max. | 5 x10 ⁶ |
| | | | Ave. | 2.88 x10 ⁶ |

2. MECHANICAL PERFORMANCE :

| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|------|-------------------------------------------------------------------------------------------|------------------------------------------------------|------------------------------------------|----------------------------|
| | | | Sample | |
| 2-1 | Durability Connector shall be subjected to 50 cycles of insertion and withdrawal | Contact resistance: Less than twice of Initial | Sample | Less than twice of Initial |
| | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | 13.5 mΩ |
| | | | 2 | 14.1 mΩ |
| | | | 3 | 14.8 mΩ |
| | | | 4 | 13.6 mΩ |
| | | | 5 | 13.4 mΩ |
| | | | Min. | 13.4 mΩ |
| | | | Max. | 14.8 mΩ |
| | | | Ave. | 13.88 mΩ |
| | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | 1 | 17.8 mΩ |
| | | | 2 | 18.4 mΩ |
| | | | 3 | 18.6 mΩ |
| | | | 4 | 18.2 mΩ |
| | | | 5 | 17.9 mΩ |
| | | | Min. | 17.8 mΩ |
| | | | Max. | 18.6 mΩ |
| | | | Ave. | 18.18 mΩ |

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | | |
|--------------------------------------------|---------------------|-----------------------------------------------------------|-------------------|--------------|------------------------|----------------------------------------------------------------------------------|
| 2-2 | Pin retention force | Push pin form insulator base at speed 25± 3 mm per minute | More than 0.4 Kgf | Sample | 0.4 Kgf min. | |
| | | | | CviLux Wafer | | |
| | | | | 1 | 0.711 Kgf | |
| | | | | 2 | 0.741 Kgf | |
| | | | | 3 | 0.738 Kgf | |
| | | | | 4 | 0.758 Kgf | |
| | | | | 5 | 0.766 Kgf | |
| | | | | Min. | 0.711 Kgf | |
| | | | | Max. | 0.766 Kgf | |
| | | | | Ave. | 0.743 Kgf | |
| | | | | ACES Wafer | | |
| | | | | 1 | 0.681 Kgf | |
| | | | | 2 | 0.688 Kgf | |
| | | | | 3 | 0.703 Kgf | |
| | | | | 4 | 0.711 Kgf | |
| | | | | 5 | 0.689 Kgf | |
| | | | | Min. | 0.681 Kgf | |
| | | | | Max. | 0.711 Kgf | |
| | | | | Ave. | 0.694 Kgf | |
| | | | | 2-3 | Mating/Unmating Forces | Measure the force required to mate/unmate connector at speed 25± 3 mm per minute |
| CviLux (2P) Wafer VS ACES Housing&Terminal | | | | | | |
| 1 | 0.485 | 1.011 | | | | |
| 2 | 0.465 | 1.092 | | | | |
| 3 | 0.458 | 1.052 | | | | |
| 4 | 0.446 | 0.988 | | | | |
| 5 | 0.473 | 1.005 | | | | |
| Min. | 0.446 | 0.988 | | | | |
| Max. | 0.485 | 1.092 | | | | |
| Ave. | 0.465 | 1.030 | | | | |
| ACES (2P) Wafer VS ACES Housing&Terminal | | | | | | |
| 1 | 0.699 | 1.211 | | | | |
| 2 | 0.713 | 1.198 | | | | |
| 3 | 0.652 | 1.252 | | | | |
| 4 | 0.725 | 1.235 | | | | |
| 5 | 0.753 | 1.205 | | | | |
| Min. | 0.652 | 1.198 | | | | |
| Max. | 0.753 | 1.252 | | | | |
| Ave. | 0.708 | 1.220 | | | | |

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | | |
|-----|------------------------|----------------------------------------------------------------------------------|------------------------------------------------------|--------------------------------------------|-------|--------|
| | | | | Sample | Mate | Unmate |
| 2-3 | Mating/Unmating Forces | Measure the force required to mate/unmate connector at speed 25± 3 mm per minute | Mating Force:3.0Kg Max. Unmating Force:0.4Kg Min. | CviLux (4P) Wafer VS ACES Housing&Terminal | | |
| | | | | 1 | 0.785 | 1.693 |
| | | | | 2 | 0.975 | 1.799 |
| | | | | 3 | 0.799 | 1.689 |
| | | | | 4 | 0.822 | 1.749 |
| | | | | 5 | 0.838 | 1.808 |
| | | | | Min. | 0.785 | 1.689 |
| | | | | Max. | 0.975 | 1.808 |
| | | | | Ave. | 0.844 | 1.748 |
| | | | | ACES (4P) Wafer VS ACES Housing&Terminal | | |
| | | | | 1 | 1.249 | 2.245 |
| | | | | 2 | 1.188 | 1.994 |
| | | | | 3 | 1.238 | 1.988 |
| | | | | 4 | 1.196 | 2.122 |
| | | | | 5 | 1.177 | 2.288 |
| | | | | Min. | 1.177 | 1.988 |
| | | | | Max. | 1.249 | 2.288 |
| | | | | Ave. | 1.210 | 2.127 |

3.ENVIRONMENTAL PERFORMANCE:

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|-----|----------------|-----------------------------------------------------|----------------------------------|---------------------------------------|---------|
| | | | | Sample | 90% min |
| 3-1 | Solder ability | Soldering time:3±0.5second Soldering pot:245±5°C | Minimum: 90% of immersed area | CviLux Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |
| | | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |



| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|------|-------------------------|-----------------------------------------------------------------|---------------------------------------|---------------------------------------|-----------|
| 3-2 | Resistance to Soldering | Soldering pot:250~260°C Soldering times: 20 ±0.5 second Max. | No change | Sample | No change |
| | | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |
| | | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |
| | | | | Less than 20 mΩ | Sample |
| | | | CviLux Wafer VS ACES Housing&Terminal | | |
| | | | 1 | | 8.8 mΩ |
| | | | 2 | | 8.7 mΩ |
| | | | 3 | | 9.2 mΩ |
| | | | 4 | | 9.1 mΩ |
| | | | 5 | | 9.3 mΩ |
| | | | Min. | | 8.7 mΩ |
| | | | Max. | | 9.3 mΩ |
| | | | Ave. | | 9.02 mΩ |
| | | | ACES Wafer VS ACES Housing&Terminal | | |
| | | | 1 | | 14.1 mΩ |
| | | | 2 | | 14.5 mΩ |
| | | | 3 | | 14.8 mΩ |
| | | | 4 | 14.7 mΩ | |
| 5 | 14.6 mΩ | | | | |
| Min. | 14.1 mΩ | | | | |
| Max. | 14.8 mΩ | | | | |
| Ave. | 14.54 mΩ | | | | |



| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | | |
|---------------------------------------|-----------------------|-------------------|-------------------------------------|------------------------------------------|---------------------------------------|----------------|
| 3-3 | Heat aging | 85±2°C , 96 hours | No change | Sample | No change | |
| | | | | CviLux Wafer VS ACES Housing&Terminal | | |
| | | | | 1 | OK | |
| | | | | 2 | OK | |
| | | | | 3 | OK | |
| | | | | 4 | OK | |
| | | | | 5 | OK | |
| | | | | ACES Wafer VS ACES Housing&Terminal | | |
| | | | | 1 | OK | |
| | | | | 2 | OK | |
| | | | | 3 | OK | |
| | | | | 4 | OK | |
| | | | | 5 | OK | |
| | | | | Dielectric strength: To pass para 1-2 | Sample | 500 V 1 minute |
| | | | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | | Pass | |
| | | | 2 | | Pass | |
| | | | 3 | | Pass | |
| | | | 4 | | Pass | |
| | | | 5 | | Pass | |
| | | | ACES Wafer VS ACES Housing&Terminal | | | |
| | | | 1 | | Pass | |
| | | | 2 | | Pass | |
| | | | 3 | | Pass | |
| | | | 4 | | Pass | |
| | | | 5 | | Pass | |
| | | | More than 100 MΩ | | Sample | 100 MΩ min. |
| CviLux Wafer VS ACES Housing&Terminal | | | | | | |
| 1 | 0.6 x10 ⁶ | | | | | |
| 2 | 0.5 x10 ⁶ | | | | | |
| 3 | 0.5 x10 ⁶ | | | | | |
| 4 | 0.6 x10 ⁶ | | | | | |
| 5 | 0.5 x10 ⁶ | | | | | |
| Min. | 0.5 x10 ⁶ | | | | | |
| Max. | 0.6 x10 ⁶ | | | | | |
| Ave. | 0.54 x10 ⁶ | | | | | |

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT |
|-----|------------|------------------------------------------------------------------------------------|------------------------|---------------------------------------|
| 3-3 | Heat aging | 85±2°C , 96 hours | More than 100 MΩ | ACES Wafer VS ACES Housing&Terminal |
| | | | | 1 1.2 x10 ⁶ |
| | | | | 2 1.0 x10 ⁶ |
| | | | | 3 1.0 x10 ⁶ |
| | | | | 4 1.2 x10 ⁶ |
| | | | | 5 0.8 x10 ⁶ |
| | | | | Min. 0.8 x10 ⁶ |
| | | | | Max. 1.2 x10 ⁶ |
| | | | | Ave. 1.04 x10 ⁶ |
| | | | Less than 40 mΩ | Sample 40 mΩ max. |
| | | | | CviLux Wafer VS ACES Housing&Terminal |
| | | | | 1 12.8 mΩ |
| | | | | 2 13.5 mΩ |
| | | | | 3 13.8 mΩ |
| | | | | 4 12.9 mΩ |
| | | | | 5 13.5 mΩ |
| | | | | Min. 12.8 mΩ |
| | | | | Max. 13.8 mΩ |
| | | | | Ave. 13.3 mΩ |
| | | | | ACES Wafer VS ACES Housing&Terminal |
| | | | | 1 16.8 mΩ |
| | | | | 2 16.9 mΩ |
| | | | | 3 17.2 mΩ |
| | | | | 4 17.9 mΩ |
| | | | | 5 17.6 mΩ |
| | | | | Min. 16.8 mΩ |
| | | | | Max. 17.9 mΩ |
| | | | | Ave. 17.28 mΩ |
| 3-4 | Humidity | 40±2°C , 90-95%RH , 96 hours measurement must be taken within 30 min. after tested | Appearance : No damage | Sample No damage |
| | | | | CviLux Wafer VS ACES Housing&Terminal |
| | | | | 1 OK |
| | | | | 2 OK |
| | | | | 3 OK |
| | | | | 4 OK |
| | | | | 5 OK |
| | | | | ACES Wafer VS ACES Housing&Terminal |
| | | | | 1 OK |
| | | | | 2 OK |
| | | | | 3 OK |
| | | | | 4 OK |
| | | | | 5 OK |



| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | | | |
|--------------|------------------------------------------------------------------------------------|---------------------------------------------------|---------------------------------------|-------------|---------------------------------------|----------------|
| | | | Sample | TEST RESULT | | |
| 3-4 Humidity | 40±2°C , 90-95%RH , 96 hours measurement must be taken within 30 min. after tested | Contact resistance: Less than twice of initial | Sample | 40mΩ max | | |
| | | | CviLux Wafer VS ACES Housing&Terminal | | | |
| | | | 1 | 13.9 mΩ | | |
| | | | 2 | 14.5 mΩ | | |
| | | | 3 | 14.6 mΩ | | |
| | | | 4 | 13.5 mΩ | | |
| | | | 5 | 13.8 mΩ | | |
| | | | Min. | 13.5 mΩ | | |
| | | | Max. | 14.6 mΩ | | |
| | | | Ave. | 14.06 mΩ | | |
| | | | ACES Wafer VS ACES Housing&Terminal | | | |
| | | | 1 | 18.6 mΩ | | |
| | | | 2 | 18.5 mΩ | | |
| | | | 3 | 19.2 mΩ | | |
| | | | 4 | 18.4 mΩ | | |
| | | 5 | 18.2 mΩ | | | |
| | | Min. | 18.2 mΩ | | | |
| | | Max. | 19.2 mΩ | | | |
| | | Ave. | 18.58 mΩ | | | |
| | | Dielectric strength: To pass para 1-2 | | | | 500 V 1 minute |
| | | | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | | | 1 | Pass |
| | | | | | 2 | Pass |
| | | | | | 3 | Pass |
| | | | | | 4 | Pass |
| | | | | | 5 | Pass |
| | | | | | ACES Wafer VS ACES Housing&Terminal | |
| 1 | Pass | | | | | |
| 2 | Pass | | | | | |
| 3 | Pass | | | | | |
| 4 | Pass | | | | | |
| 5 | Pass | | | | | |

| | ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|-----|-------------|---------------------------------------------------------------------------------------------------------------------------------------|------------------|---------------------------------------|-----------------------|
| 3-4 | Humidity | 40±2°C , 90-95%RH , 96 hours measurement must be taken within 30 min. after tested | More than 100 MΩ | Sample | 100 MΩ min. |
| | | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | | 1 | 0.6 x10 ⁶ |
| | | | | 2 | 0.8 x10 ⁶ |
| | | | | 3 | 0.3 x10 ⁶ |
| | | | | 4 | 0.5 x10 ⁶ |
| | | | | 5 | 0.3 x10 ⁶ |
| | | | | Min. | 0.3 x10 ⁶ |
| | | | | Max. | 0.8 x10 ⁶ |
| | | | | Ave. | 0.5 x10 ⁶ |
| | | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | | 1 | 1.1 x10 ⁶ |
| | | | | 2 | 1.1 x10 ⁶ |
| | | | | 3 | 0.7 x10 ⁶ |
| | | | | 4 | 0.6 x10 ⁶ |
| | | | | 5 | 0.8 x10 ⁶ |
| | | | | Min. | 0.6 x10 ⁶ |
| | | | | Max. | 1.1 x10 ⁶ |
| | | | | Ave. | 0.86 x10 ⁶ |
| 3-5 | Temperature | One cycle consists of: (1)-55 +0/-3 °C ,30 min. (2)Room temp. 10-15 min. (3)85 +3/-0 °C ,30 min. (4)Room temp. 10-15 min. | No change | Sample | No change |
| | | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |
| | | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | | 1 | OK |
| | | | | 2 | OK |
| | | | | 3 | OK |
| | | | | 4 | OK |
| | | | | 5 | OK |



| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | | |
|-------------------------------------|-----------------------|---------------------------------------------------------------------------------------------------------------------------------------|------------------------------------------|---------------------------------------|----------------|
| 3-5 | Temperature | One cycle consists of: (1)-55 +0/-3 °C ,30 min. (2)Room temp. 10-15 min. (3)85 +3/-0 °C ,30 min. (4)Room temp. 10-15 min. | Dielectric strength: To pass para 1-2 | Sample | 500 V 1 minute |
| | | | | CviLux Wafer VS ACES Housing&Terminal | |
| 1 | Pass | | | | |
| 2 | Pass | | | | |
| 3 | Pass | | | | |
| 4 | Pass | | | | |
| 5 | Pass | | | | |
| ACES Wafer VS ACES Housing&Terminal | | | | | |
| 1 | Pass | | | | |
| 2 | Pass | | | | |
| 3 | Pass | | | | |
| 4 | Pass | | | | |
| 5 | Pass | | | | |
| 3-5 | Temperature | More than 100 MΩ | | Sample | 100 MΩ min. |
| | | | CviLux Wafer VS ACES Housing&Terminal | | |
| | | | 1 | 0.5 x10 ⁶ | |
| | | | 2 | 0.3 x10 ⁶ | |
| | | | 3 | 0.5 x10 ⁶ | |
| | | | 4 | 0.2 x10 ⁶ | |
| | | | 5 | 0.3 x10 ⁶ | |
| | | | Min. | 0.2 x10 ⁶ | |
| | | | Max. | 0.5 x10 ⁶ | |
| | | | Ave. | 0.36 x10 ⁶ | |
| | | | ACES Wafer VS ACES Housing&Terminal | | |
| | | | 1 | 0.6 x10 ⁶ | |
| | | | 2 | 0.7 x10 ⁶ | |
| | | | 3 | 0.5 x10 ⁶ | |
| 4 | 0.4 x10 ⁶ | | | | |
| 5 | 0.5 x10 ⁶ | | | | |
| Min. | 0.4 x10 ⁶ | | | | |
| Max. | 0.7 x10 ⁶ | | | | |
| Ave. | 0.54 x10 ⁶ | | | | |

| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|--------------------|---------------------------------------------------------------------------------------------------------------------------------------|-----------------------|---------------------------------------|------------|
| | | | Sample | |
| 3-5 Temperature | One cycle consists of: (1)-55 +0/-3 °C ,30 min. (2)Room temp. 10-15 min. (3)85 +3/-0 °C ,30 min. (4)Room temp. 10-15 min. | Less than 40 mΩ | Sample | 40 mΩ max. |
| | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | 15.2 mΩ |
| | | | 2 | 15.3 mΩ |
| | | | 3 | 15.5 mΩ |
| | | | 4 | 15.8 mΩ |
| | | | 5 | 15.6 mΩ |
| | | | Min. | 15.2 mΩ |
| | | | Max. | 15.8 mΩ |
| | | | Ave. | 15.48 mΩ |
| | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | 1 | 20.1 mΩ |
| | | | 2 | 20.8 mΩ |
| | | | 3 | 19.9 mΩ |
| | | | 4 | 20.6 mΩ |
| | | | 5 | 20.5 mΩ |
| | | | Min. | 19.9 mΩ |
| Max. | 20.8 mΩ | | | |
| Ave. | 20.38 mΩ | | | |
| 3-6 Salt spray | Temperature:35±3°C Solution:5±1% Spray time:48±4hours Measurement must be taken after water rinse | Appearance: No damage | Sample | No change |
| | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | OK |
| | | | 2 | OK |
| | | | 3 | OK |
| | | | 4 | OK |
| | | | 5 | OK |
| | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | 1 | OK |
| | | | 2 | OK |
| | | | 3 | OK |
| | | | 4 | OK |
| | | | 5 | OK |



| ITEM | TEST CONDITION | REQUIREMENT | TEST RESULT | |
|----------------|------------------------------------------------------------------------------------------------------------|---------------------------------------------------|---------------------------------------|---------|
| | | | Sample | |
| 3-6 Salt spray | Temperature:35±3°C Solution:5±1% Spray time:48±4hours Measurement must be taken after water rinse | Contact resistance: Less than twice of initial | 40 mΩ max | |
| | | | CviLux Wafer VS ACES Housing&Terminal | |
| | | | 1 | 15.2 mΩ |
| | | | 2 | 15.8 mΩ |
| | | | 3 | 16.1 mΩ |
| | | | 4 | 15.8 mΩ |
| | | | 5 | 15.6 mΩ |
| | | | Min. | 15.2 mΩ |
| | | | Max. | 16.1 mΩ |
| | | | Ave. | 15.7 mΩ |
| | | | ACES Wafer VS ACES Housing&Terminal | |
| | | | 1 | 20.9 mΩ |
| | | | 2 | 21.1 mΩ |
| | | | 3 | 21.8 mΩ |
| | | | 4 | 21.5 mΩ |
| | | | 5 | 21.5 mΩ |
| | | | Min. | 20.9 mΩ |
| Max. | 21.8 mΩ | | | |
| Ave. | 21.36 mΩ | | | |